

Line 21, delete "(1)" and "(P)".

Line 23, delete "(7)" and "([beta])".

Line 24, delete "(Figure 1)".

IN THE CLAIMS:

Please cancel claims 1-8, without prejudice.

Please add the following new claims:

9. (New) An ellipsometer measurement apparatus for determining a thickness of a film applied on a substrate, comprising:

- a light source emitting a beam;
- a transmitting optical system conveying the beam to an incidence point on the substrate, the substrate reflecting the beam from the incidence point;
- a photodetector device;
- a receiving optical system conveying the reflected beam to the photodetector device, the receiving optical system including an analyzer, a polarization direction of the beam and of the analyzer being modified in time relative to one another;
- an evaluation device evaluating intensity changes in the reflected beam and determining the film thickness as a function of the intensity changes; and
- an angle measurement device sensing an angle of the reflected beam relative to a tangential plane of the substrate at the incidence point, the evaluation device determining the film thickness as a function of the sensed angle.

10. (New) The measurement apparatus according to claim 9, wherein the angle measurement device includes a photodetector unit that is position-sensitive in at least one of an X and Y direction, an angle of reflection being calculated from position data and distance data with an evaluation stage.

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11. (New) The measurement apparatus according to claim 10, wherein the intensity changes and the position data are sensed with a ~~same~~ photodetector.

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12. (New) The measurement apparatus according to claim 10, wherein the photodetector unit includes two position-sensitive photodetectors arranged at a distance from the incidence point in a beam path of the reflected beam, the angle of reflecting being calculated based on differing positions of the reflected beam on the two position-sensitive photodetectors.

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13. (New) The measurement apparatus according to claim 12, further comprising:

a beam splitter arranged in the beam path of the reflected beam in front of the two position-sensitive photodetectors, each of the two position-sensitive photodetectors receiving a partial beam of the reflected beam.

14. (New) The measurement apparatus according to claim 9, further comprising:

a converging lens arranged in front of the photodetector device.

15. (New) The measurement apparatus according to claim 9, wherein the transmitting optical system and the receiving optical system are integrated into a common carrier, the carrier having a three-point support for placement of the film.

16. (New) The measurement apparatus according to claim 9, wherein the transmitting optical system includes a polarizer and a $\lambda/4$ plate in a beam path of the beam, and wherein one of the polarizer and the analyzer is arranged in rotationally driven fashion about an axis normal to a surface of the one of the polarizer and the analyzer.